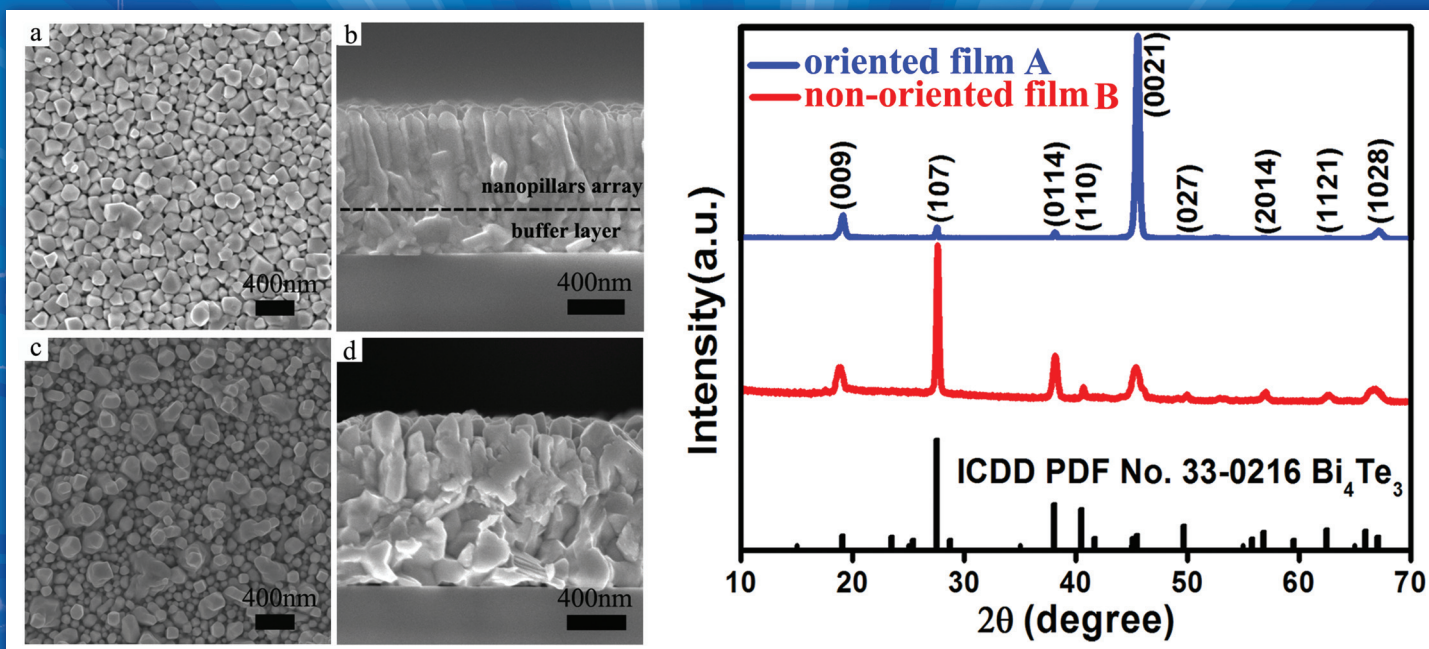
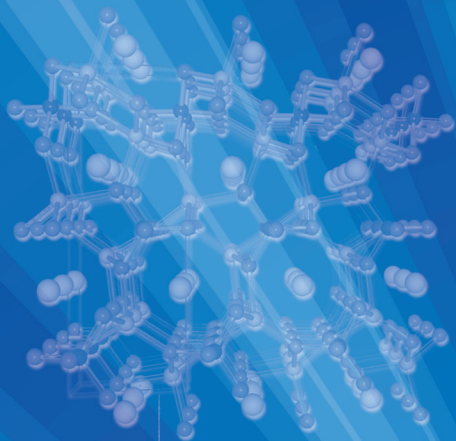


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On the Cover: This Issue's cover shows figures from the manuscript "Preparation of Bi_4Te_3 highly oriented nanopillars array film with enhanced electrical properties" by Jing Wu, et al. The top-surface and cross-sectional morphologies were obtained by field emission scanning electron microscopy (FE-SEM). The morphology of the oriented film are shown in (a) and (b). The morphology of the non-oriented film is shown in the lower pair. On the right side are the XRD patterns for the two films, clearly showing the extensive orientation. The microstructural orientation in the nanopillars array film led to nearly doubling of the thermoelectric transport properties.

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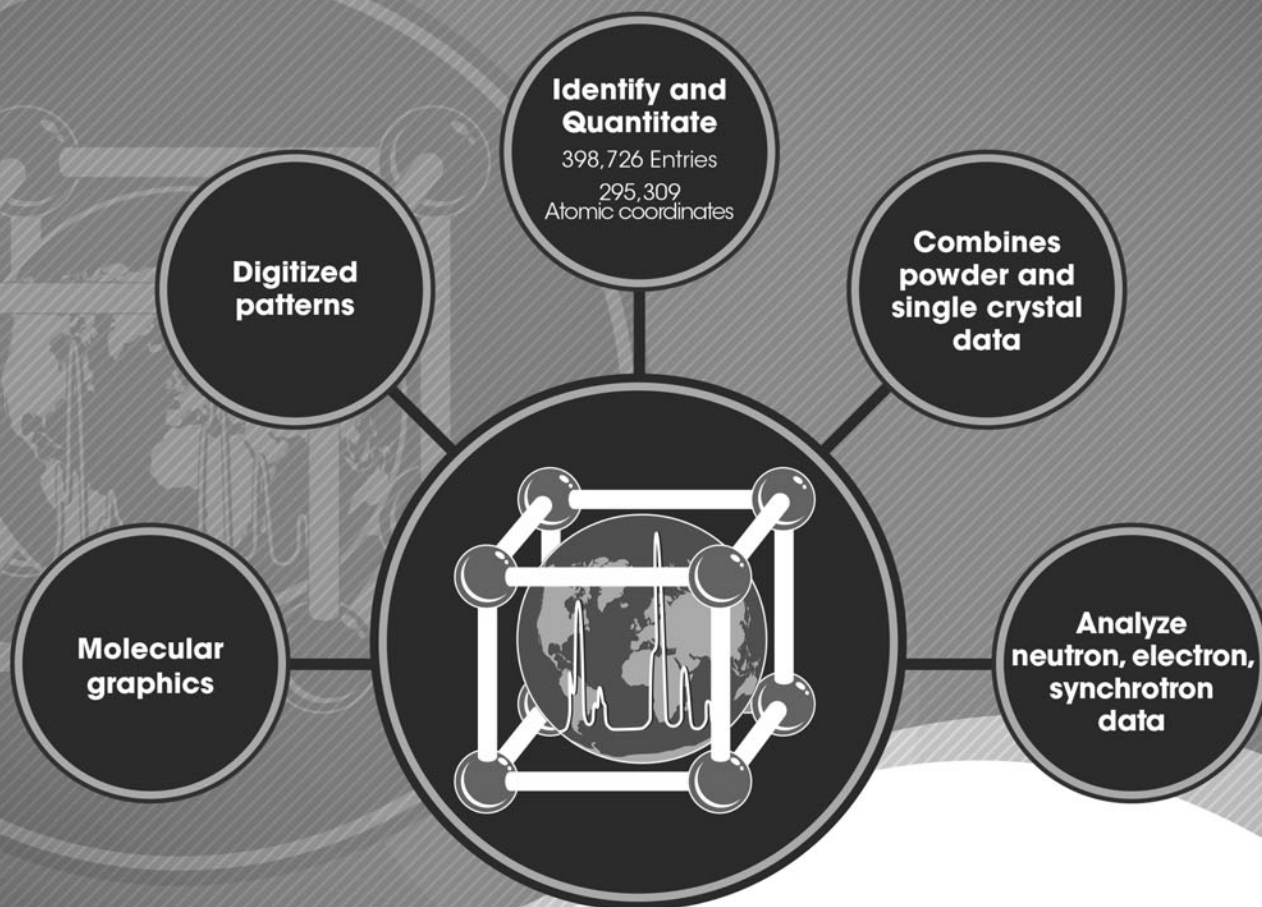
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